



Matrix Semiconductor, Inc.

OTP MATRIX® 3-D MEMORY - 32PIN TSOP

16MB, 32MB, 64MB

DATA SHEET

DOCUMENT NUMBER: **DS004**
REVISION: **1.11**
REVISION DATE: 06-24-05

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1.0 REVISION HISTORY

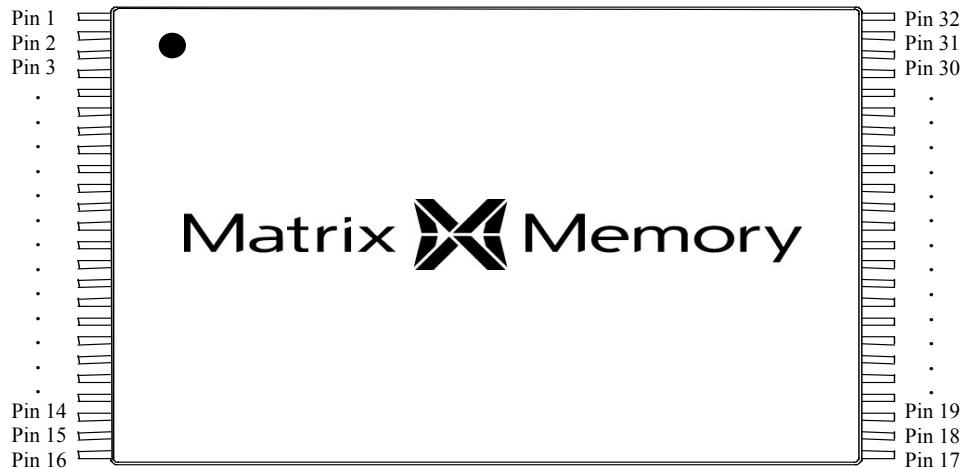
| REVISION | HISTORY | REV. DATE | REMARK |
|----------|--------------------|-----------|---|
| 1.0 | Production Release | 7/30/04 | Prior Rev. history may be accessed through archived files. |
| 1.1 | Updated Release | 5/11/05 | Removed 48TSOP, Updated Part Numbers, Removed Bad Page Specification |
| 1.11 | Updated Release | 6/24/05 | Inserted Matrix trademarks; corrected numbering & spacing; omitted 48TSOP reference from 8.0. |

TABLE OF CONTENTS

| | | |
|-------------|--|-----------|
| 1.0 | REVISION HISTORY | II |
| 2.0 | PIN DESCRIPTION | 2 |
| 2.1 | PIN PLACEMENT | 2 |
| 2.2 | MATRIX® 3-D MEMORY (3DM) PIN MAP | 2 |
| 2.3 | DETAILED PIN DESCRIPTION | 3 |
| 3.0 | ARRAY ORGANIZATION | 4 |
| 4.0 | OPERATING COMMAND REQUIREMENTS | 4 |
| 5.0 | PROGRAMMING REQUIREMENTS..... | 5 |
| 5.1 | PROGRAMMING DATA REQUIREMENTS..... | 5 |
| 5.2 | PAGE REWRITE SPECIFICATION | 5 |
| 6.0 | OPERATION MODES AND COMMAND TABLES | 5 |
| 6.1 | OPERATING MODES | 5 |
| 6.2 | READ MODES | 5 |
| 6.3 | VALID READ OPERATING MODES | 6 |
| 6.4 | DEVICE CODES..... | 6 |
| 6.5 | STATUS REGISTER OUTPUTS..... | 6 |
| 6.6 | PERFORMANCE SPECIFICATIONS | 6 |
| 6.7 | AC OPERATING REQUIREMENTS | 7 |
| 6.8 | OPERATING ENVIRONMENT | 8 |
| 6.8.1 | DC REQUIREMENTS..... | 8 |
| 6.8.2 | ABSOLUTE MAXIMUM RATING..... | 8 |
| 6.8.3 | CAPACITANCE | 8 |
| 6.8.4 | STORAGE CONDITION | 8 |
| 6.8.5 | LIFETIME AND DATA RETENTION | 8 |
| 6.8.6 | OPERATING TEMPERATURE | 9 |
| 7.0 | TIMING SPECIFICATION | 9 |
| 7.1 | COMMAND LATCH CYCLE | 9 |
| 7.2 | ADDRESS LATCH CYCLE | 9 |
| 7.3 | INPUT DATA LATCH CYCLE | 10 |
| 7.4 | SEQUENTIAL OUT CYCLE AFTER READ | 11 |
| 7.5 | STATUS READ CYCLE | 11 |
| 7.6 | READ1 AND READ2 OPERATIONS (READ ONE PAGE) | 12 |
| 7.7 | READ1 AND READ2 OPERATIONS (INTERCEPTED BY CE#)..... | 12 |
| 7.8 | READ3 OPERATION (READ ONE PAGE) | 13 |
| 7.9 | SEQUENTIAL ROW READ OPERATION (WITHIN A BLOCK) | 13 |
| 7.10 | PAGE WRITE OPERATION | 14 |
| 7.11 | MANUFACTURE & DEVICE ID READ OPERATION..... | 14 |
| 8.0 | IDENTITY 3DM PROTOCOL | 15 |
| 9.0 | POWER ON REQUIREMENTS..... | 15 |
| 10.0 | READ/BUSY# LOAD REQUIREMENTS | 16 |
| 11.0 | PACKAGE DIMENSIONS | 17 |
| 11.1 | 32-PIN TSOP | 17 |
| 12.0 | PART NUMBER INFORMATION..... | 17 |

2.0 PIN DESCRIPTION

2.1 PIN PLACEMENT



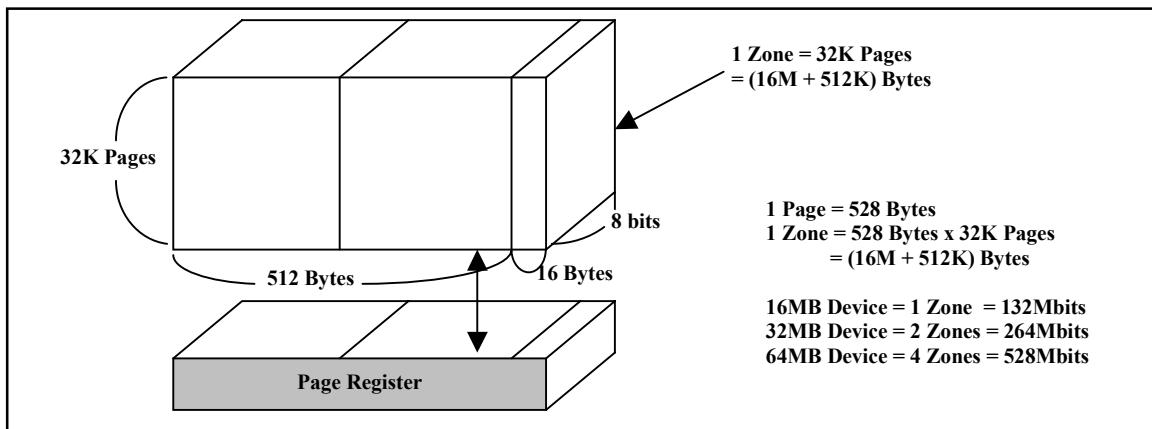
2.2 MATRIX® 3-D MEMORY (3DM) PIN MAP

| PIN | | PIN | | PIN | | PIN | |
|-----|-----------------|-----|-----|-----|-----------------|-----|-----------------|
| 1 | NC | 9 | GND | 17 | NC | 25 | GND |
| 2 | NC | 10 | NC | 18 | NC | 26 | V _{DD} |
| 3 | R/B# | 11 | NC | 19 | NC | 27 | IO ₅ |
| 4 | NC | 12 | CLE | 20 | IO ₁ | 28 | IO ₆ |
| 5 | RE# | 13 | ALE | 21 | IO ₂ | 29 | IO ₇ |
| 6 | CE# | 14 | WE# | 22 | IO ₃ | 30 | IO ₈ |
| 7 | NC | 15 | WP# | 23 | IO ₄ | 31 | ID3DM |
| 8 | V _{DD} | 16 | NC | 24 | NC | 32 | NC |

2.3 DETAILED PIN DESCRIPTION

| PIN NAME | PIN FUNCTION | DETAILED PIN DESCRIPTION |
|-----------------------------------|----------------------|--|
| IO ₁ - IO ₈ | Data Input/Outputs | Handles the input and output of addresses, commands, and data. |
| CE# | Chip Enable | Acts as the device selection signal. When set to 'H' in the read state, the standby mode is assumed. In the Busy state during the execution of write operations (R/B# = L), both 'H' and 'L' are accepted. (Standby will not be assumed when 'H') |
| CLE | Command Latch Enable | Enables commands to be sent to the internal command register of the device. Setting the level to 'H' when the WE# signal falls and rises causes the data on the I/O terminals to be written into the command register |
| ALE | Address Latch Enable | Controls whether data is sent to the internal address register or the internal data register in the device. By setting the level to 'H' when the WE# signal falls and rises, the data present at the I/O terminals is written into the address register as address data. By setting the level to 'L' when the WE# signal falls and rises, the data present at the I/O terminals is written into the data register as input data |
| RE# | Read Enable | Enables the output of data serially from the I/O terminals. From the time RE# falls, valid output data will be present at the I/O terminals after tREA, and the internal column address counter advances (+1) |
| WE# | Write Enable | Used to write data present at the I/O terminals into the device |
| WP# | Write Protect | Prohibits writing. At 'L', the operation of the internal high voltage generating circuit is reset. Normally, the system is operated with this signal 'H', but if the power supply signals are irregular (ON/OFF, etc.), this signal should be 'L' in order to protect stored data from unexpected operations. In the event that the V _{DD} voltage is outside the range in which correct operation is assured, it is recommended that the level be set to 'L' |
| R/B# | Ready/Busy Output | Serves as open drain output that indicates the internal operating conditions of the device. During write and read operations, Busy (R/B# L) is output. Ready is automatically output when the operation is finished |
| ID3DM | Identify 3DM | Disables the Identify 3DM Protocol when tied to V _{DD} . See the "Identify 3DM Protocol" section of this datasheet for more details. |
| GND | Ground Input | Ground |
| V _{DD} | Power Supply | Power Supply Voltage |

3.0 ARRAY ORGANIZATION



4.0 OPERATING COMMAND REQUIREMENTS

Command, address and data are all written through I/O's by bringing WE# to low while CE# is low. Data is latched on the rising edge of WE#. Command Latch Enable (CLE) and Address Latch Enable (ALE) are used to multiplex command and address respectively, via the I/O pins. All commands require one bus cycle. The 64Mbyte physical space requires 26 addresses, thereby requiring four cycles for byte-level addressing: column address, low row address and high row address, in that order. Page Read and Page Write need the same four address cycles following the required command input. Device operations are selected by writing specific commands into the command register. The following table defines the specific commands of the Matrix® 3DM chip.

| COMMAND | OP CYCLE | VALID DURING BUSY |
|-------------------|----------|-------------------|
| Serial Data Input | 80 h | N |
| Read1 | 00 h | N |
| Read2 | 01 h | N |
| Read3 | 50 h | N |
| Reset | FF h | Y |
| Page Write | 10 h | N |
| Status Read | 70 h | Y |
| ID Read | 90 h | N |
| * ID3DM | 90 h | N |

*Three consecutive IDREAD cycles to release the part from write protect mode.

5.0 PROGRAMMING REQUIREMENTS

5.1 PROGRAMMING DATA REQUIREMENTS

| ITEM | SIZE | REMARKS |
|--------------------|---------|------------------------------|
| Minimum word size* | 64 bits | Data must be octbyte aligned |

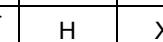
*Partial pages must be programmed by padding the new input data with data previously in memory to form one complete page

5.2 PAGE REWRITE SPECIFICATION

| SYMBOL | PARAMETER | MIN | MAX |
|--------|--|-----|-----|
| Now | Maximum number of programming commands allowed for each page | - | 64 |

6.0 OPERATION MODES AND COMMAND TABLES

6.1 OPERATING MODES

| MODE | CLE | ALE | CE# | WE# | RE# | WP# |
|---------------|-----|-----|-----|--|---|-----|
| Command Input | H | L | L |  | H | X |
| Address Input | L | H | L |  | H | X |
| Data Input | L | L | L |  | H | X |
| Data Output | L | L | L | H |  | X |
| While writing | X | X | X | X | X | H |
| Write Protect | X | X | X | X | X | L |

H: V_{IH} L: V_{IL} X = V_{IH} or V_{IL}

6.2 READ MODES

| COMMAND | 1 ST CYCLE | POINTER |
|---------|-----------------------|------------|
| Read1 | 00 h | 0 to 255 |
| Read2 | 01 h | 256 to 511 |
| Read3 | 50 h | 512 to 527 |

6.3 VALID READ OPERATING MODES

| MODE | CLE | ALE | CE# | WE# | RE# | D ₁ – D ₈ | STATUS |
|-----------------|-----|-----|-----|-----|-----|---------------------------------|---------|
| Read Mode | L | L | L | H | L | D _{OUT} | Active |
| Output Deselect | L | L | L | H | H | Z | Active |
| Standby | L | L | H | H | X | Z | Standby |

6.4 DEVICE CODES

| MEMORY SIZE | DEVICE CODE |
|-------------|-------------|
| 16MB | 73h |
| 32MB | 75h |
| 64 MB | 76h |

6.5 STATUS REGISTER OUTPUTS

| PIN | STATUS | “0” | “1” |
|-----------------|---|-----------|---|
| IO ₁ | Pass or Fail (only valid if IO ₆ = “1”) | Pass | Write Failure: Failed repair during Write |
| IO ₂ | Reserved | Default | -- |
| IO ₃ | Reserved | Default | -- |
| IO ₄ | Reserved | Default | -- |
| IO ₅ | Reserved | Default | -- |
| IO ₆ | Reserved | Default | -- |
| IO ₇ | Ready or Busy | Busy | Ready |
| IO ₈ | Write Protect | Protected | Not Protected * |

* Before ID3DM is issued, this location will indicate protected, after ID3DM protocol or if ID3DM pin is pulled high, it will reflect the status of the WP# pin.

6.6 PERFORMANCE SPECIFICATIONS

| SYMBOL | PARAMETER | MIN | TYPICAL | MAX |
|-----------------------|---------------------------------|-----|---------|--------|
| t _{PROG} | Write time | - | 400 us* | 8 ms** |
| t _R | Data transfer time | - | 200 us | 460 us |
| t _{RSTread} | Device reset time (read cycle) | - | 2 us | 10 us |
| t _{RSTwrite} | Device reset time (write cycle) | - | 2 us | 10 us |

*t_{PROG} typ is defined as 50% 0 data pattern in programming factory at nominal conditions.

**t_{PROG} max may occur during rare redundancy self-repair operation.

6.7 AC OPERATING REQUIREMENTS

| SYMBOL | PARAMETER | MIN | MAX | SYMBOL | PARAMETER | MIN | MAX |
|--------------------|-------------------------------|--------|-------|---------------------|---|--------|--------|
| t _{CYCLE} | Cycle time | 50 ns | -- | t _{CEH} | CE# high hold time (last serial read) | 100 ns | -- |
| t _{CLS} | CLE setup to WE# | 0 ns | -- | t _{REAI} D | RE# access time (ID read) | -- | 35 ns |
| t _{CLH} | CLE hold to WE# | 10 ns | -- | t _{RHZ} | RE# high to output high impedance | -- | 30 ns |
| t _{CS} | CE# setup to WE# | 0 ns | -- | t _{REH} | RE# high hold time | 15 ns | -- |
| t _{CH} | CE# hold to WE# | 10 ns | -- | t _{IR} | Ouput high impedance to RE# low | 0 ns | -- |
| t _{WP} | WE# pulse width | 25 ns | -- | t _{RS} T0 | RE# access time (status read) | -- | 35 ns |
| t _{ALS} | ALE setup to WE# | 0 ns | -- | t _{CS} T0 | CE# access time (status read) | -- | 45 ns |
| t _{ALH} | ALE hold WE# | 10 ns | -- | t _{WHR} | WE# high to RE# low | 30 ns | -- |
| t _{DS} | Data setup to WE# | 20 ns | -- | t _{WHC} | WE# high to CE# low | 30 ns | -- |
| t _{DH} | Data hold to WE# | 10 ns | -- | t _{AR1} | ALE lot to RE# low (Add. Reg. & ID read) | 100 ns | -- |
| t _{WC} | Write cycle time | 50 ns | -- | t _{CR} | CE# lot to RE# low (Data Reg. & ID read) | 100 ns | -- |
| t _{WH} | WE# high hold time | 15 ns | -- | t _{WB} | WE# high to busy | -- | 100 ns |
| t _{RP} | Read pulse width | 35 ns | -- | t _{AR2} | ALE low to RE# low (read cycle) | 50 ns | -- |
| t _{RC} | Read cycle time | 50 ns | -- | t _{RB} | Last RE# high to busy (sequential read) | -- | 200 ns |
| t _{REA} | RE# access time (serial data) | -- | 35 ns | t _{CRY} | CE# high to ready: R = (V _{DDmax} - V _{OLmax}) / (I _{OL} +I _L) | -- | 2 us |
| T _{WW} | WP# high to WE# low | 100 ns | -- | t _{CHZ} | CE# high to output high impedance | -- | 20 ns |
| T _{RR} | Ready to RE# low | 20 ns | -- | | | | |

6.8 OPERATING ENVIRONMENT

6.8.1 DC REQUIREMENTS

| SYMBOL | PARAMETER | MIN | MAX |
|-------------|---|----------------|------------------|
| V_{DD} | Supply voltage | 2.7 V | 3.6 V |
| V_{IH} | Input high voltage | 2.2 V | $V_{DD} + 0.3$ V |
| V_{IL} | Input low voltage | -0.3 V | 0.6 V |
| V_{OH} | Ouput high voltage ($I_{OH} = -400\mu A$) | 2.4 V | - |
| V_{OL} | Output low voltage ($I_{OL} = 2.1mA$) | - | 0.4 V |
| I_{CC1}^* | Read current (typ) | 20 mA | |
| I_{CC2} | Read current (max) | 30 mA | |
| I_{CC3}^* | Write current (typ) | 40 mA | |
| I_{CC4} | Write current (max) | 80 mA | |
| I_{CCS} | Standby current | 100 μA | |
| I_{LI} | Input Leakage | $\pm 10 \mu A$ | |
| I_{LO} | Ouput Leakage | $\pm 10 \mu A$ | |

* Typical values measured at room temperature and 3.3V.

6.8.2 ABSOLUTE MAXIMUM RATING

| SYMBOL | PARAMETER | MIN | MAX |
|----------|--------------------|--------|------------------------|
| V_{DD} | Supply Voltage | | 4.6 V |
| V_{IH} | Input high voltage | -- | $V_{DD}+0.3 \leq 4.6V$ |
| V_{IL} | Input low voltage | -0.3 V | -- |

6.8.3 CAPACITANCE

| SYMBOL | PARAMETER | MIN | MAX |
|--------|--|-------|-------|
| C_L | Capacitance due to input or output pin | 10 pF | 15 pF |

6.8.4 STORAGE CONDITION

| SYMBOL | PARAMETER | MIN | MAX |
|---------|----------------------------------|-----------|--------|
| Tstore | Storage Temperature Requirements | -25 °C | 150 °C |
| Lshelf* | Shelf Lifetime | >10 Years | |

*Shelf lifetime is specified with an average temperature of $25^\circ C \pm 10^\circ C$

6.8.5 LIFETIME AND DATA RETENTION

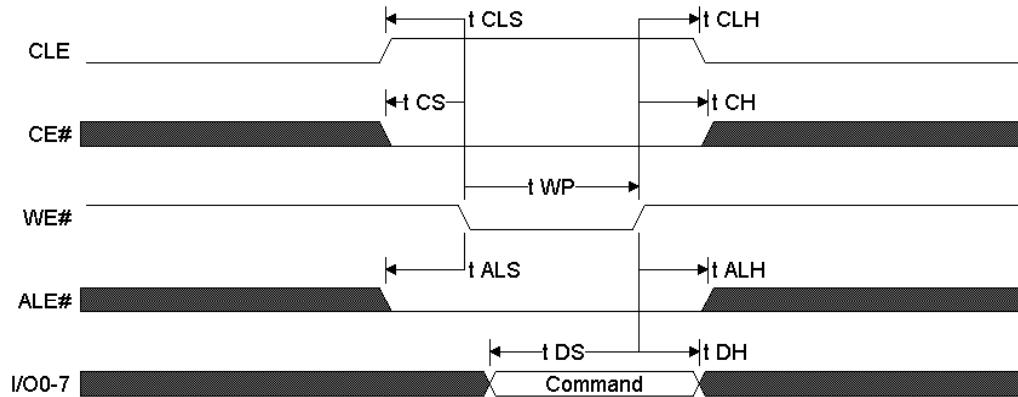
| SYMBOL | PARAMETER | MIN | MAX |
|--------|-------------------------|----------|-----|
| Ldr | Data Retention Lifetime | 10 Years | - |

6.8.6 OPERATING TEMPERATURE

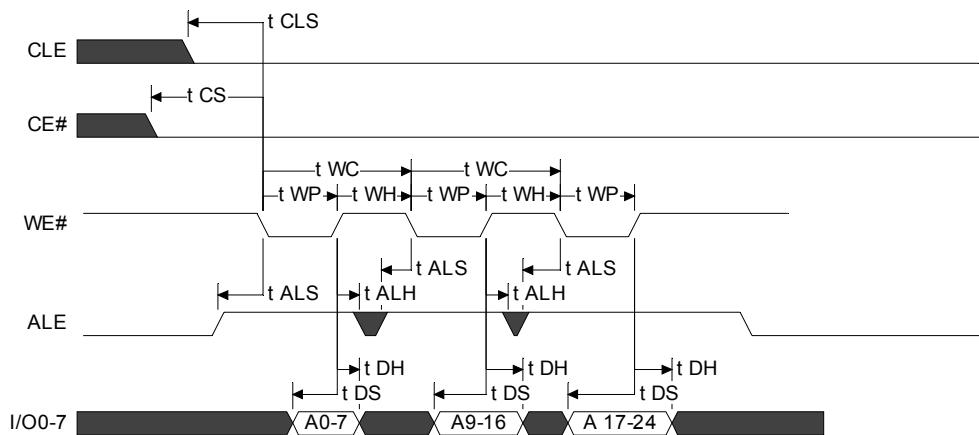
| SYMBOL | PARAMETER | MIN | MAX |
|--------|--------------------------------------|------|-------|
| Toper | Operational Temperature Requirements | 0 °C | 70 °C |

7.0 TIMING SPECIFICATION

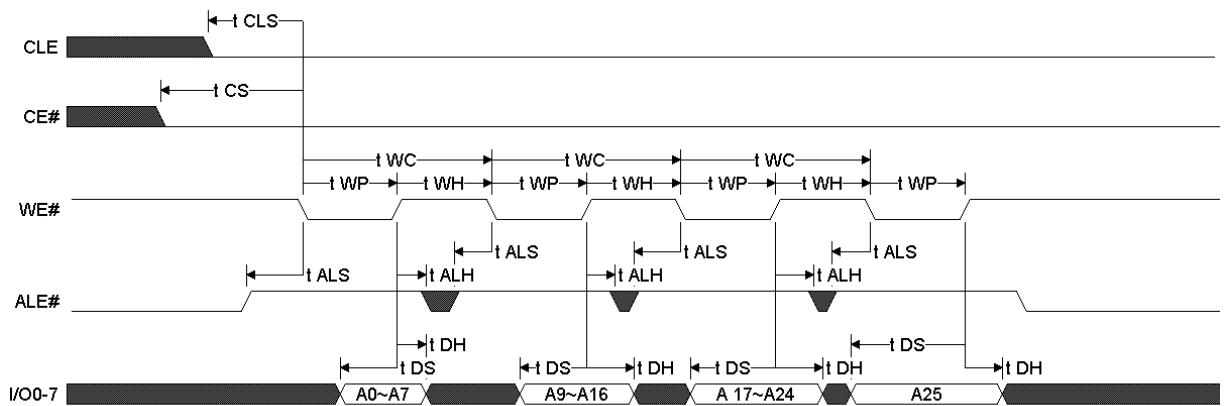
7.1 COMMAND LATCH CYCLE



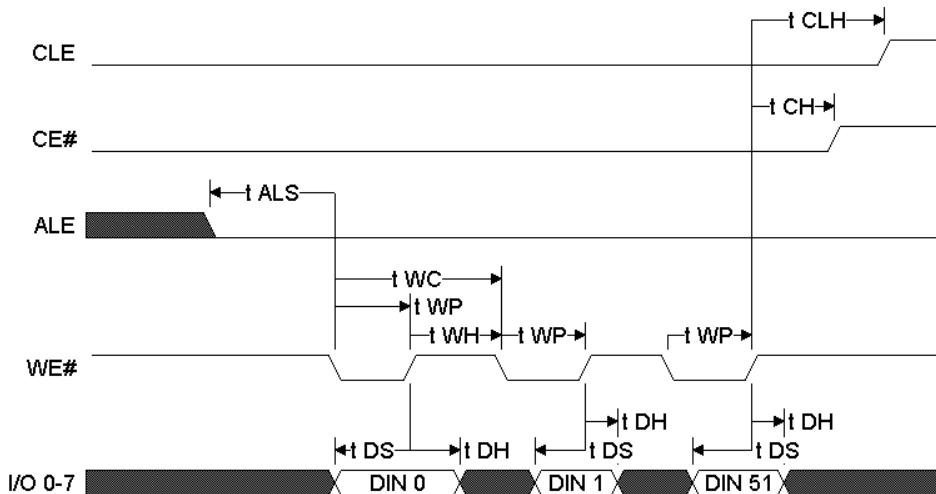
7.2 ADDRESS LATCH CYCLE (Address Cycle for 128Mb and 256Mb)



(Address Cycle for 512Mb)

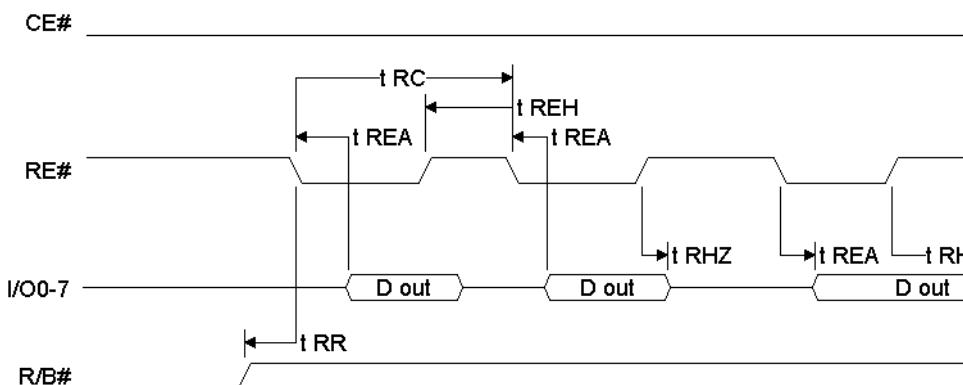


7.3 INPUT DATA LATCH CYCLE

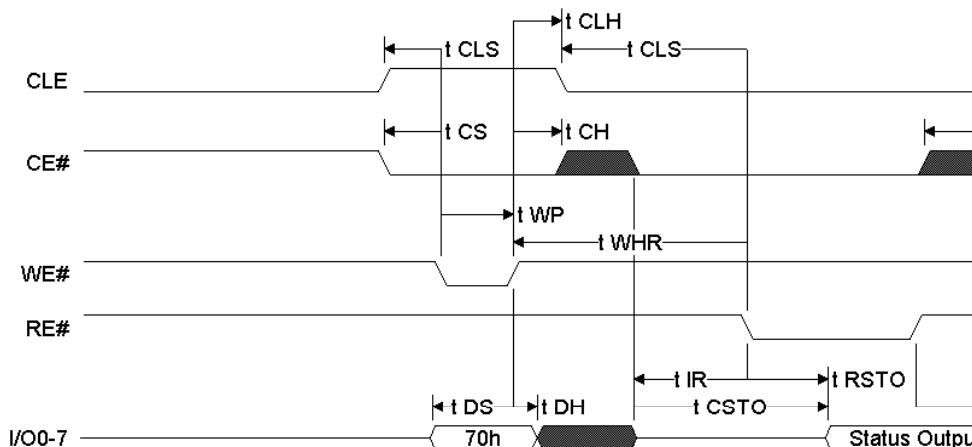


7.4 SEQUENTIAL OUT CYCLE AFTER READ

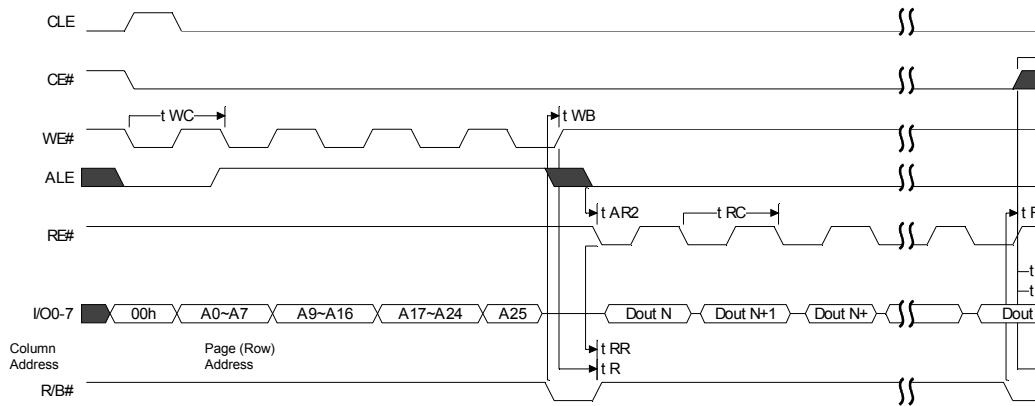
(CLE = L, WE# = H, ALE = H)



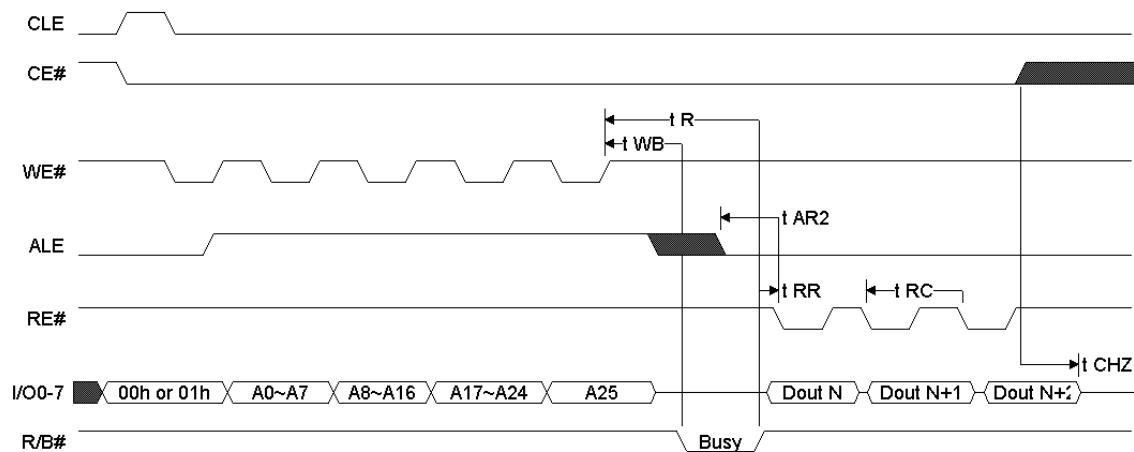
7.5 STATUS READ CYCLE



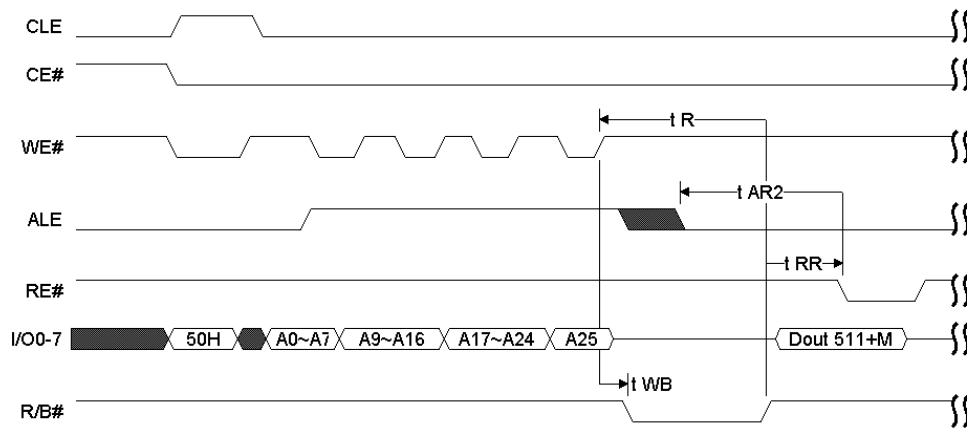
7.6 READ1 AND READ2 OPERATIONS (READ ONE PAGE)



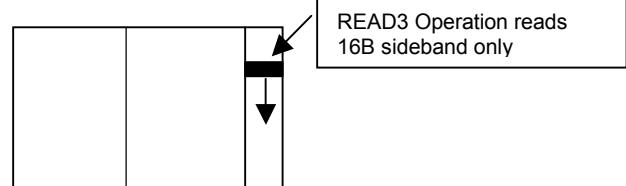
7.7 READ1 AND READ2 OPERATIONS (INTERCEPTED BY CE#)



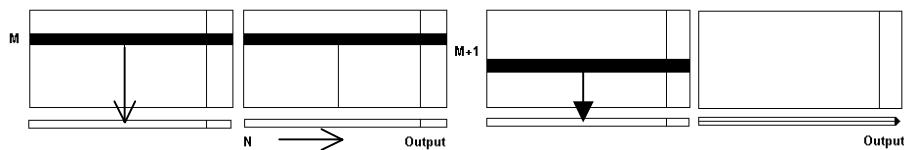
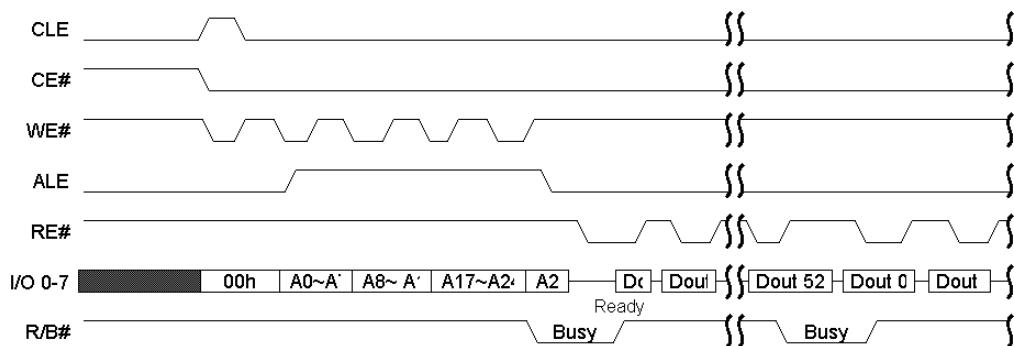
7.8 READ3 OPERATION (READ ONE PAGE)



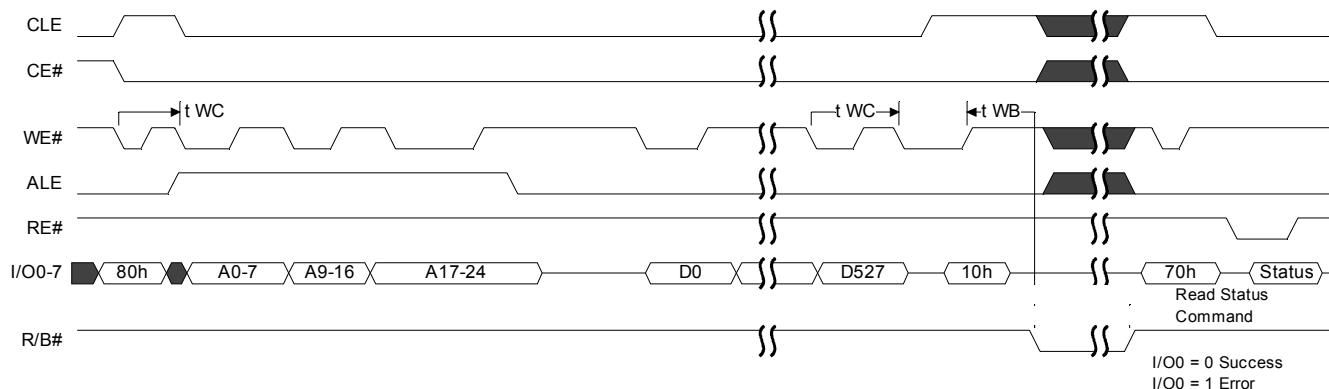
M Address
A0~A3: Valid Address
A4~A7: Don't Care



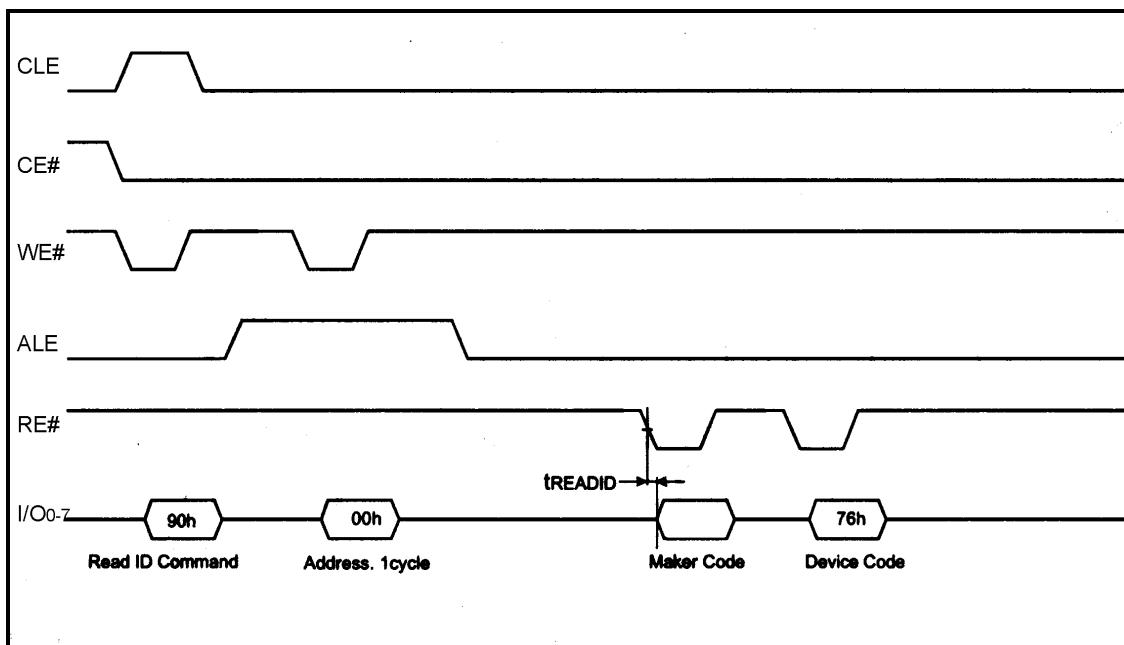
7.9 SEQUENTIAL ROW READ OPERATION (WITHIN A BLOCK)



7.10 PAGE WRITE OPERATION



7.11 MANUFACTURE & DEVICE ID READ OPERATION



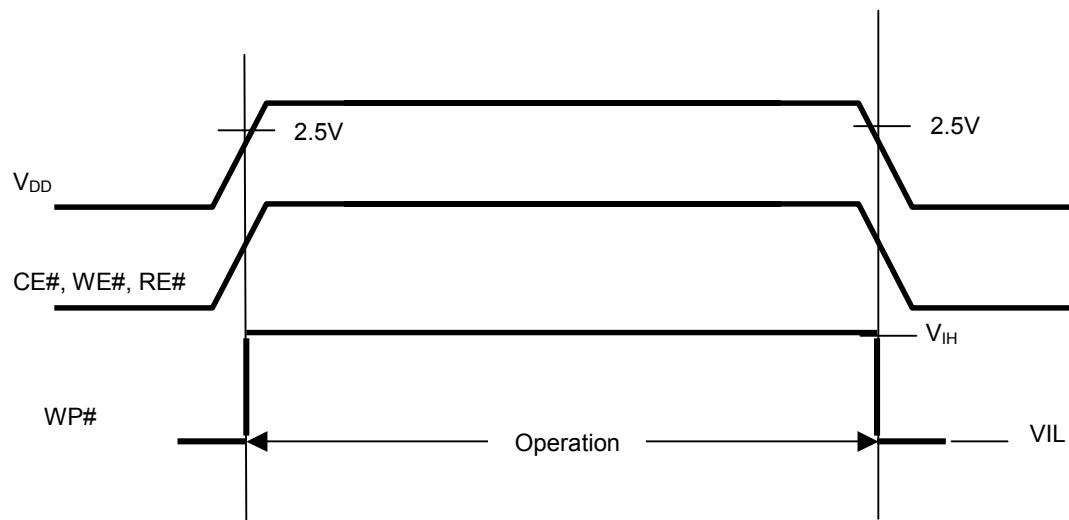
8.0 IDENTITY 3DM PROTOCOL

The “Identify 3DM” protocol is used to prevent unintentional overwriting of data on Matrix’s memory devices from hosts which are not enabled for Matrix media. A host may identify its ability to use Matrix® 3DM during a data session using this protocol or it may bypass the protocol in hardware.

PROTOCOL: After an initial power-on, the Matrix® 3DM module is set to a “read only” state. In this state, write operations are not permitted. In order to allow write operations, an ID3DM command must be performed by sending three consecutive IDREAD commands to the device. This sequence tells the memory that the host device is enabled to use Matrix® 3DM. Once this command is executed the card is “unlocked,” and write operations are permitted.

HARDWARE BYPASS: Alternatively, the “Identify 3DM” protocol may be bypassed in hardware by setting Pin 31 (TSOP32) to V_{DD}. This allows all supported commands to be issued immediately, bypassing the protocol above.

9.0 POWER ON REQUIREMENTS



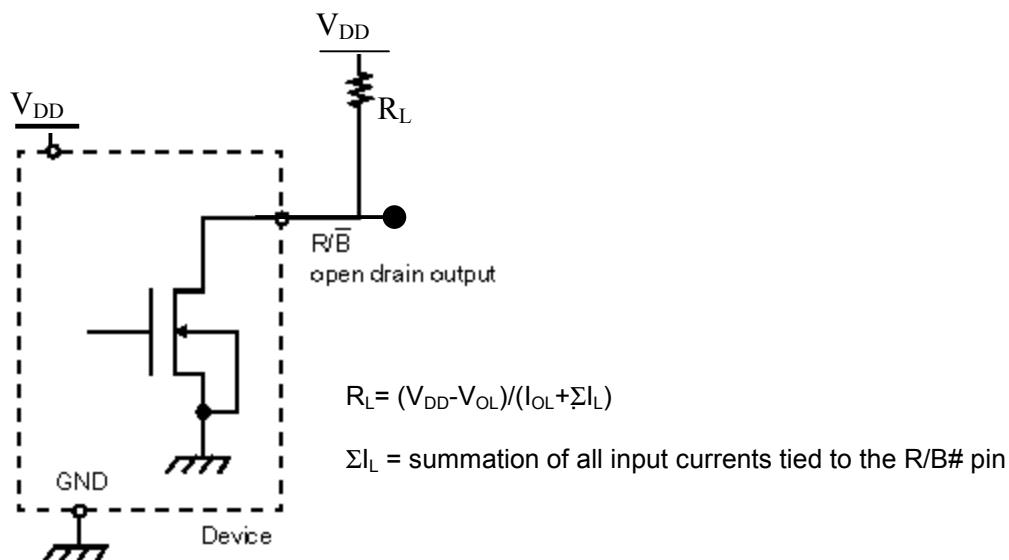
To ensure proper startup a RESET command should be entered after V_{DD} has been established.

10.0 READ/BUSY# LOAD REQUIREMENTS

The Ready/Busy# signal requires a pull-up resistor for this open-drain output. For the resistance (R_L) refer to the following equation:

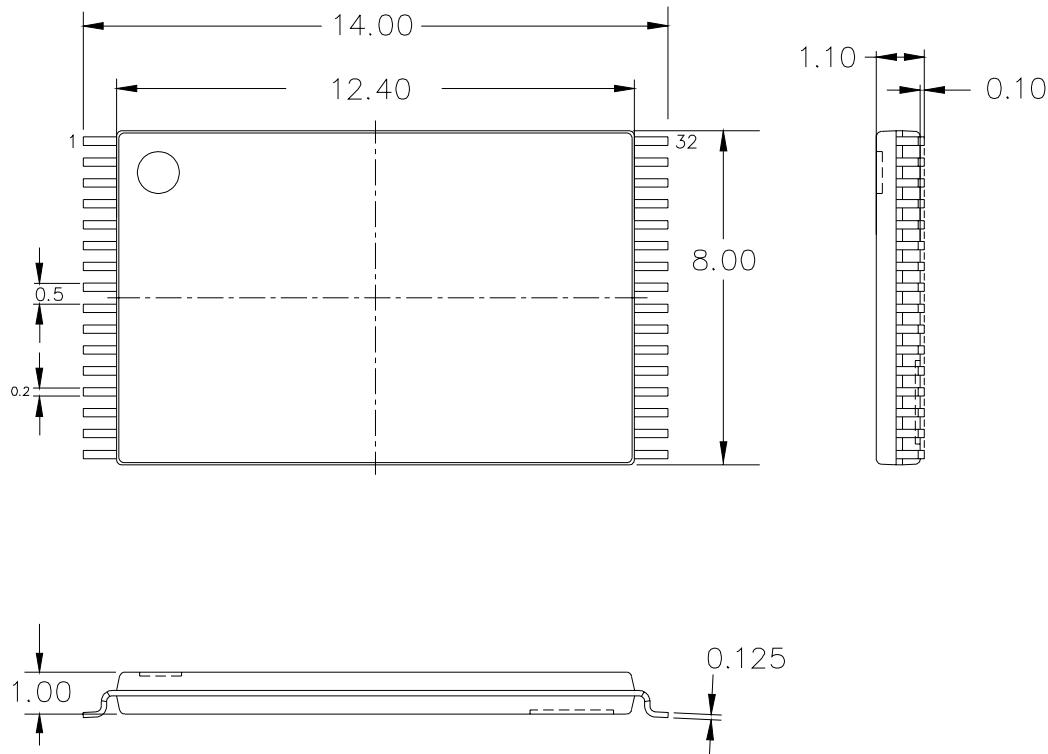
$$R_L = \frac{V_{DD}(\text{Max.}) - V_{OL}(\text{Max.})}{I_{OL} + \sum I_L}$$

$\sum I_L$ is the sum of the input current of all devices connected to the Ready/Busy# pin.



11.0 PACKAGE DIMENSIONS

11.1 32-PIN TSOP



Notes:

- All dimensions listed are nominal values listed in mm.
- Limited volume 48-pin TSOP available for samples only.
- Alternative packages may be available upon request.

12.0 PART NUMBER INFORMATION

| Memory Capacity | Package Description | Ordering Part Number | Operational Part Number (On TSOP) |
|-----------------|---------------------|----------------------|-----------------------------------|
| 16MB | 32-pin TSOP | 3DM-16TS-T004 | 11252-XX-XX |
| 16MB | 32-pin TSOP Pb-Free | 3DM-16TS-T008 | 11277-XX-XX |
| 32MB | 32-pin TSOP Pb-Free | 3DM-32TS-T006 | 11278-XX-XX |
| 64MB | 32-pin TSOP Pb-Free | 3DM-64TS-T005 | 11219-XX-XX |